multiLane

MEASUREMENT SOLUTIONS

BROCHURE | 2025

Contents

Innovation for the Next Generation

Since 2006, MultiLane has been offering high speed test and measurement equipment for data communications. We help chart industry evolution and accelerate the adoption of new technologies with a complete cycle support of data center test solutions encompassing IC and transceiver characterization, host line card test, and link testing. We provide a range of form factors and architectures, from portable instruments, to stand-alone benchtop instruments to automated test platforms. We also assist our customer base with compliance and interoperability test services. MultiLane provides leading solutions for developers, module vendors, interconnect and cable manufacturers, network installers, and data center operators with high-performance, scalable equipment, with a comprehensive set of development solutions for MSA and backplane connectors.

The MultiLane portfolio encompasses optical and electrical oscilloscopes, Bit Error Rate Testers (BERTs), Time Domain Reflectometers (TDR) for semiconductor wafer level testing, SerDes, TIAs, cable testing, and active interconnects.

5
International Branches

200
More than 200 products released

500
Over 500 customers

Product Portfolio

Test solution instrumentation is a core value proposition at MultiLane, brought to life by the feedback of tier-one networking and data center equipment vendors and operators. The High-Speed I/O market depends on the agility of vendors like MultiLane to ensure cutting-edge designs can be released quickly as appetites for increased bandwidth capacity remain insatiable.

MultiLane's agility enables us to quickly respond to customer needs with our domain expertise and proprietary technology. Our comprehensive product offerings include optical and electrical oscilloscopes, bit error rate testers, TDR cable testers, interconnect products, and fully automated transceiver test solutions. This portfolio enables the adoption of new technologies that developers, manufacturers, and installers demand in this fast-paced industry. We understand the complexity of solutions required for physical-layer tests at these high speeds as well as the competitive economic realities of the sector. MultiLane's specialists provide high-end, scalable, solutions that meet and exceed customer expectations.

Next-Gen Measurement Solutions

Ultra-High-Throughput Copper Validation

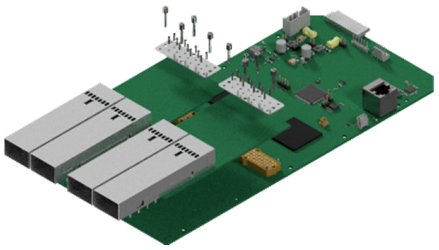
Copper remains a vital component of current and next-gen networks, with high-density copper interconnects key components in AI clusters. With thousands of differential pairs and even a single point of failure capable of bringing down an entire system, rapid, comprehensive testing is essential.

Given the critical issues of reliability, cost, and scale that have come to define this generation of network technology, MultiLane has found that Bit Error Rate Testers (BERTs) serve as more effective solutions than traditional forms of testing.

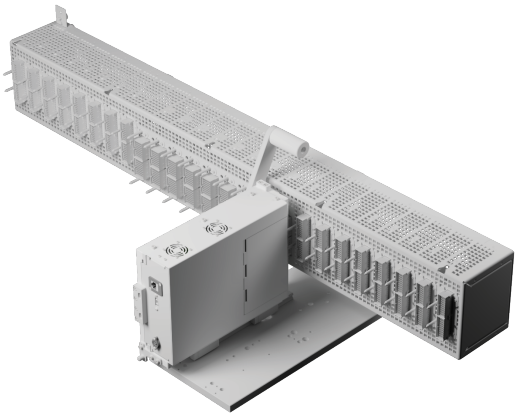
BERTs offer much faster testing times, lower Total Cost of Ownership, simpler calibration, and fewer false positives than conventional cable testing. BERTs also offer higher resolution testing compared to traditional alternatives: covering key pass/fail metrics, like BER, alongside more detailed measurements like Signal to Noise Ratio (SNR), PRBS locking, and Tx Squelch that can point to specific mechanical failures (poor mating, bent pins, etc.) in cable manufacturing.

MultiLane solutions compound these benefits with an ultra-high-density BERT that greatly accelerate the pace of development and deployment: the ML7064E-LX. A scalable solution that can test at the required speeds, the ML7064E-LX can test up to 64 channels per unit at 112Gbps/lane and PCIe gen 5, 6, and 7, with multiple units fitted into the cartridge testing solution for a testing setup to match the requirements of passive copper interconnects.

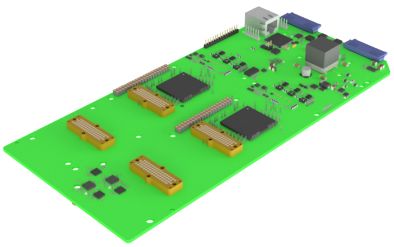
The ML7064E-LX offers maximum versatility and can be fitted with daughter cards of any connector type, from MSA connectors like OSFP and OSFP-XD, to 64-channel backplane connectors, or even custom connectors for unique applications.



ML7064E-LX with OSFP daughter cards



Cartridge and parallel testing enclosure



ML7064E-LX with no daughter cards

ML7064E-LX Key Features

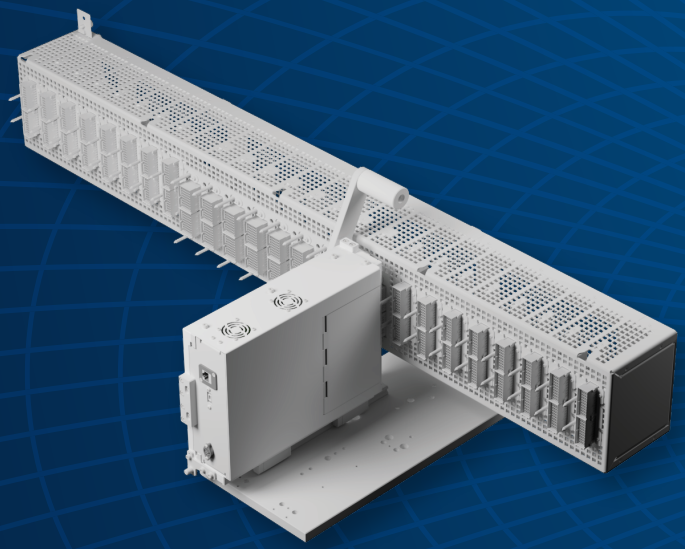
- Up to 64 channel per module
- Up to 112G/lane
- Supports various ethernet rates including 53.125Gbaud and PCIe 3, 5, 6, and 7
- Customizable Mechanical Enclosure

ML7032F-LX Key Features

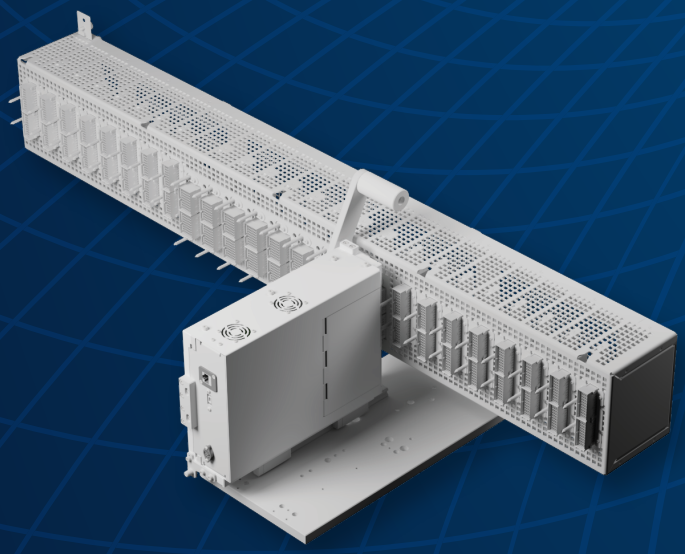
- Up to 32 channel per module
- Up to 224Gbps/lane
- Supports various ethernet rates including 53.125Gbaud and PCIe 3, 5, 6, and
- Customizable Mechanical Enclosure
- Available August 2025

Ultra-Dense BERT Family

The ML7064E-LX and ML7032F-LX are the highest density family of BERTs in the industry, with 64 channels at 112Gbps/lane and 32 channels at 224Gbps/lane, respectively. Built for high scale testing and maximum versatility, the BERTs offer ultra-high throughput validation, with replaceable daughter cards to test any type of interconnect. Multiple units can be fitted into a cartridge testing solution for testing high-density passive copper interconnects.



ML7064E-LX
Available Now



ML7032F-LX
Available August 2025

Next-Gen Measurement Solutions

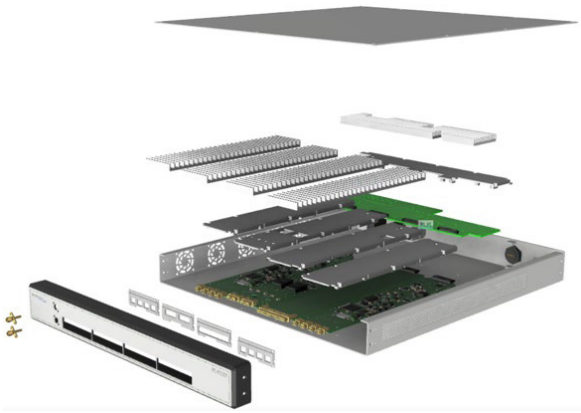
MultiWave Test Platform

Your Instrument, Your Way

The MultiWave Test Platform (MWTP) provides the perfect balance of flexibility and ease of use. The expanded enclosure allows us to offer a series of models and options, placing up to 4 MultiLane instruments as MultiWave (MW) modules into a customer-specified MWTP. The resulting instrument allows for specific user-defined testing in a fixed package, ideal for lab, rack-and-stack, ATE, and production setups, offering a range of solutions for any testing and characterization needs.

Refreshed Look and Feel

Next-gen MultiLane instruments bring with them a new look and feel for the new generation. Including the MW7004F-L 224Gbps/lane BERT.



MWTP Applications

- Post silicon Validation
- V&V Characterization
- End-of-Line Board-level test
- High-speed component manufacturing
- Field Failure Analysis
- High-density passive and active interconnect characterization & testing

	Part Number	Description	Channels	Signal Format	Output Amplitude	Details
BERT	**MW7004F-L**	4-Lane 224Gbps/lane BERT	4	PAM4/NRZ	0-800 mVpp	• Up to 120Gbaud with 106.25Gbaud; 120Gbit/s; 53.125Gbaud; 26.5625Gbaud and 25.78125Gbit/s • Up to 40db equalization • Suitable for active and passive interconnect testing
	MW7008E-LFN	8-Lane 112Gbps/lane Long Reach BERT	-	PAM4/NRZ	0-800 mVpp	• 34 dB loss equalization • Line rates for PCIe Gen 3, 5, 6, and 7, LPO, and automotive applications • SMPS connectors
DSO	**MW6004-70-E**	4-channel electrical DSO	4	67GHz	-	• SMPX connectors
	MW6004-35-E	4-channel electrical DSO	4	35GHz	-	• SMPX connectors
AWG	**MW9004E**	Differential Arbitrary Waveform Generator	4	PAM4/8/6/NRZ	-	• Sampling rate up to 96GSa/s • AWG Mode: A wide variety of pre-programmed waveforms. • PPG Mode: NRZ and PAM4 • Analog bandwidth up to 30GHz
	MW9004F	Differential Arbitrary Waveform Generator	4	PAM4/8/6/NRZ/ Custom Patterns	-	• Sampling rate up to 150GSa/s • AWG Mode: A wide variety of pre-programmed waveforms. • PPG Mode: NRZ and PAM4 • Analog bandwidth over 65GHz • all channels synchronizable and multi-module synchronizable

Specialty Instruments

Working at the forefront of high-speed I/O innovation, MultiLane offers pre-built solutions tailored to some of the most common testing applications required by the industry. These Specialty Instruments target specific – and common – usecases, ensuring an accelerated time to market for technologies in high demand.

ML8008FX-SIA

ML8008FX-SIA – Signal Integrity Analyzer

The ML8008FX-SIA Signal Integrity Analyzer is a high-throughput tester optimized for validating passive copper solutions such as switch-based flyover cables, DACs, and backplanes. It supports a wide range of signal integrity measurements, including Sdd21, intra-pair skew (IPS), crosstalk, and common-mode measurements. With automated differential S-parameter validation, multi-channel impedance profiling, and ultra-fast testing capabilities, the ML8008FX-SIA delivers reliable results for high-volume production with a low cost of ownership. Its rapid, high-throughput performance makes it an ideal solution for demanding manufacturing environments.

ML7064E-L-UMT

Universal Module Tester

The MultiLane Universal Module Tester line comprises high channel count BERTs designed to validate ultra-high density backplanes/interconnects. With 64 and 128 lane count models – the ML7064E-L-UMT and ML7128E-LFX-UMT respectively – the UMT line acts as rapid, high-throughput debuggers in any environment, including single-click pass/fail report generation. Equally built for a variety of interconnect testing cases, the UMT comes with replaceable daughter cards, creating a modular front panel that can be tailored to any pluggable and backplane harness.

UMT Applications

- RMA
- Rapid go/no go testing for LPOs, active and passive interconnect
- Quick debugging during testing, identifies issues in seconds
- Field failure analysis
- BERT validation for backplane cables

ML7128E-LFX-UMT

	Part Number	Description	Channels	Data Format	Details
Instrument	**ML8008FX-SIA**	8-lane 224G Signal Integrity Analyzer	8	PAM4/NRZ	• Insertion Loss and Crosstalk Measurements • Impedance Profiling and IPS Measurements • Scalable for High-Density Applications
	ML7064E-L-UMT	64-lane 112G BERT Interconnect tester	64	PAM4/NRZ	• High density interconnect tester • Replaceable daughter cards for a fully customizable front panel
	ML7128E-LFX-UMT	128-lane 112G BERT Interconnect tester	128	PAM4/NRZ	• Ultra-high density interconnect tester • Replaceable daughter cards for a fully customizable front panel

Instruments

Bit Error Rate Testers

Bit error rate testers (BERTs) are a foundational block of high-speed communications testing. These instruments generate a digital test pattern, typically a pseudorandom binary sequence (PRBS) and/or square wave, which drives a device under test (DUT). Following the transmission through the link, the error detector in the BERT captures the signal. This setup can be used to evaluate the performance of a transmitter, receiver, or optical system. MultiLane supports general-purpose BERTs which connect through precision co-axial cables, as well as BERTs that present an MSA-compliant port for pluggables built directly into the instrument. The resulting signals' eye diagrams can be viewed by connecting a Digital Sampling Oscilloscope (DSO) to the setup.

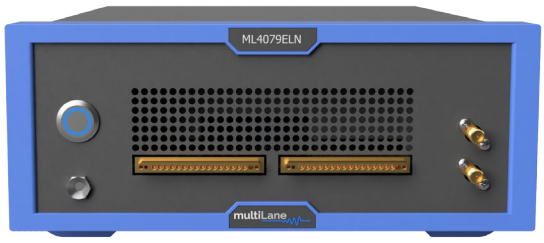
A BERT needs to be tailored to the characteristics of the DUT.

Key considerations include:

- Baud rate
- Number of channels
- Modulation format (e.g., NRZ, PAM-4, etc.)
- Test pattern (e.g., PRBS15)
- Signal amplitude
- Port type (e.g., QSFP-DD)
- Form factor (e.g., portable, chassis, etc.)

ML7004F-L Key Features

- Up to 40dB Rx Equalization
- Data Rates: 106.25; 53.125; 26.5625Gbaud/lane PAM4 and their derivatives
- Independent control of inner eye levels



ML4079ELN Key Features

- 34dB equalization on the Rx side
- Real HW FEC
- PCIe gen 3 5 6 and 7
- Ethernet Rates
- Low rates (automotive)
- Noise Injection

ML7004F-L

The high-speed I/O market has an urgent need for BERT validation for high-density 224Gbps/lane interconnects. The latest MultiLane BERT, the ML7004F-L, features 4 224Gbps lanes and 40 dB SerDes equalization, giving customers a head-start developing for 1.6T networks and long reach applications. The ML7004F-L is available as a standalone instrument, or a MultiWave Module, the MW7004F-L, which can be used to create a 16-channel 224Gbps/lane BER tester for high-density 224Gbps applications.

	Part Number	Description	Channels	Data Format	Output Amplitude	Details
General Purpose BERTs	**MW7004F-L**	4-Lane 224Gbps/lane BERT	4	PAM4/NRZ	0-800 mVpp	• 106.25; 53.125; 26.5625Gbaud/lane PAM4 • 40 dB loss equalization • SMPS connectors
	MW7008E-LFN	8-Lane 112Gbps/lane Long Reach BERT	8	PAM4/NRZ	0-800 mVpp	• 34 dB loss equalization • Line rates for PCIe Gen 3, 5, 6, and 7, LPO, and automotive applications • SMPS connectors
	ML4079ELN	8-Lane 66Gbd NRZ PAM4, 800G BERT, 34dB equalizer with PCIe gen3-5-6-7, and low-rate testing capabilities	8	PAM4/NRZ	0-800 mVpp	• 1G -- 66G PAM4/NRZ • 34dB equalization • Real HW FEC • Noise Injection • Ethernet, PCIe and low rates
	ML4079EN	8-Lane, 58 GBd NRZ & PAM4, 800G BERT with noise injection	8	PAM4/NRZ	0-1200 mVpp	• 20-29G & 36-61G PAM4/NRZ • Random and Burst Noise Injection • Random and Sinusoidal Jitter Injection
	ML4079E	8-Lane, 58 GBd NRZ & PAM4, 800G BERT	8	PAM4/NRZ	0-700 mVpp	• 23-29 & 46-56 GBd PAM4/NRZ • Real Hardware FEC (KR4/KP4 Analysis) • Dense M-SMPM connectors
	ML4039EN	4-Lane, 58 Gbd PAM4, 400G BERT with Noise Injection	4	PAM4/NRZ	0-800 mVpp	• 23-29 & 46-56 GBd PAM4/NRZ • Real Hardware FEC (KR4/KP4 Analysis) • Noise Injection (Crosstalk Interference) • Standard 2.4 mm connectors
	ML4039E	4-Lane, 58 GBd PAM4, 400G BERT	4	PAM4/NRZ	0-800 mVpp	• 23-29 & 46-56 GBd PAM4/NRZ • Real Hardware FEC (KR4/KP4 Analysis) • Standard 2.4 mm connectors
	ML4039B	4-Lane, 1.12-29 GBd NRZ & PAM4, (Gen 2), 200G BERT	4	PAM4/NRZ	0-800 mVpp	• 7 – 28.125 GBd PAM4 • 1.12–1.56, 2.24-28.125 Gbps NRZ • Standard 2.92 mm connectors

	Part Number	Description	Differential Channels	Data Format	Output Amplitude	Details
General Purpose BERTs	**ML4079D**	8-Lane, 29.5 Gbd NRZ & PAM4. 400G BERT	8	PAM4/NRZ	0-1200 mVpp	• 9-14.3 & 22-29.5 GBd PAM4 • 9-14.3 and 23.2-29.5 Gbps NRZ • FEC Emulation (KR4/KP4 Analysis) • Standard 2.92 mm connectors
	ML4039D	4-Lane, 29.5 GBd NRZ & PAM4, 200G BERT with FEC estimation	4	PAM4/NRZ	0-1200 mVpp	• 22-29.5 GBd PAM4 • 9-14.2 and 23.2-29.5 Gbps NRZ • FEC Emulation (KR4/KP4 Analysis) • Standard 2.92 mm connectors
	ML4039-BTP	Gbps NRZ, Stand Alone, 100G BERT	4	NRZ	200-800 mVpp	• 8.5-15 & 21-30 Gbps NRZ • Standard 2.92 mm connectors
	ML4039-JIT-BTP	Gbps NRZ, 100G BERT with Jitter Generation	4	NRZ	100-2000 mVpp	• 8.5-15 & 21-30 Gbps NRZ • Jitter/receiver tolerance • Standard 2.92 mm connectors

ML4079ELN

The ML4079ELN is an 8-channel, 800G BERT purpose-built for long reach applications including PCIe-Gen 3, 5, 6, and 7, automotive, transceiver and data center interconnect testing. The ML4079ELN features a wide range of line rate coverage, up to 34dB equalization, built-in AWGN noise injection, and ratio level mismatch (RLM), control, providing a single platform for testing up to 8x66 GBaud. The ML4079ELN includes transmitter equalization (3 or 7 taps FFE), and receiver equalization. The ML4079ELN can provide measurements for Signal-to-Noise Ratio (SNR), histogram measurements, and Real Time BER Measurements and FEC Measurements.

Oscilloscopes

Digital sampling oscilloscopes (DSOs) are essential tools for the characterization of a variety of active or passive DUTs. They are often used in conjunction with a BERT, which injects the digital test pattern into the channel before reaching the MultiLane DSO, leveraging critical measurement capabilities like jitter and eye diagram analysis.

When choosing a DSO, it is important to define the "scope" of your use case. MultiLane offers single channel optical and electrical systems, as well as multi-channel electrical systems to fit a wide variety of applications.

Key Features

- Extensive library of built-in DSP filters such as Bessel-Thomson, CTLE, DFE, FFE
- Comprehensive eye mask library
- Compact instrument footprint with ruggedized enclosure

MultiLane scopes can be equipped with built-in clock recovery modules to ensure a synchronous trigger for each measurement and eliminate excessive jitter from the signal.

	Part Number	Description	Electrical bandwidth (GHz)	Optical bandwidth (GHz)	Details
DSO	**MW6004-70-E**	4-channel electrical DSO	67	NA	• SMPX connectors
	MW6004-35-E	4-channel electrical DSO	35	NA	• SMPM connectors
	ML6002-70-E	Dual channel Electrical DSO	67	NA	• SMPX connectors
	ML4015E-35	Single channel Electrical DSO	35	NA	
	ML4015E-OPT-25	Single Channel Optical DSO	NA	25	
	ML4015E-2X-35	Dual Channel Electrical DSO	35	NA	
	ML4015E-2X-35-OPT-SM42	Dual Channel Electrical & Optical DSO	42	42	
	ML4015E-2X-35-OPT-33	Dual Channel Electrical & Optical DSO	33	33	

Time Domain Reflectometry

Pulsar

MultiLane Pulsar is a 4-channel Time Domain Reflectometry analyzer that simplifies troubleshooting by providing full SI insights, enabling the detection of impedance mismatches, discontinuities, and skew measurements. Pulsar is designed with scalability for parallel measurements and optimized for high throughput, making it ideal for testing high-density ports.

ML4025F-PLS

ML4025E-PLS

Full Pulsar Setup

	Part Number	Description	Rise Time (ps)	Details
TDR	**ML4025E-PLS**	Time Domain Reflectometer (TDR)	12ps	• SMPM connectors • 4-Channel differential TDR
	ML4025F-PLS	Time Domain Reflectometer (TDR)	7ps	• SMPX connectors • 4-Channel differential TDR

ML4035

The MultiLane ML4035 is a 3 in 1 TDR, BERT and DSO optimized for NRZ and PAM4 eye measurements, S-parameters evaluation and impedance profile characterization to provide full SI insights and optimize troubleshooting. It enables simultaneous testing on four channels and serves various applications such as cables and connectors testing, PCB testing and multiport host characterization.

The ML4035 is a high-throughput instrument, providing the fastest testing times in the industry to best serve high scale production.

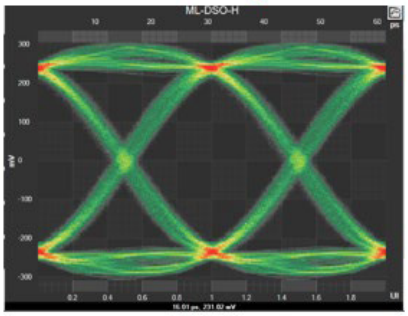
ML4035

	Part Number	Description	Bandwidth (GHz)	Data Format	Details
TDR	**ML4035**	ML4035 Time Domain Reflectometer (TDR)	35 GHz	PAM4/NRZ	• 4 Channel 35 GHz DSO • 4 Channel 56 GBd BERT (PPG and ED) • 4 Channel True-Differential TDR/TDT • Standard 2.4 mm connectors

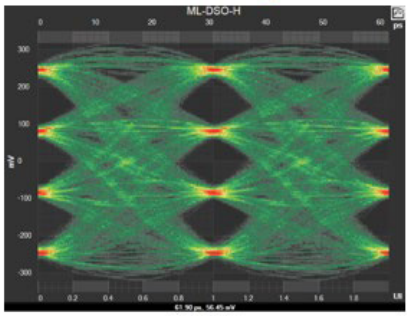
Arbitrary Waveform Generators

Arbitrary Waveform Generators (AWGs) are essential instruments for generating custom electrical waveforms in advanced testing environments. The ML9004F — our latest high-performance AWG —delivers a 150GSa/s sample rate with an analog bandwidth exceeding 65GHz. Designed for high-speed SerDes transceiver and amplifier validation, the ML9004F enables Rx jitter tolerance testing, signal integrity analysis, and compliance testing for cutting-edge standards such as PCIe, USB, MIPI, and coherent optical communications. This AWG is a powerful tool for 400G/800G ZR coherent module development and high-speed digital signal processing, offering BER and FER testing capabilities for next-generation applications.

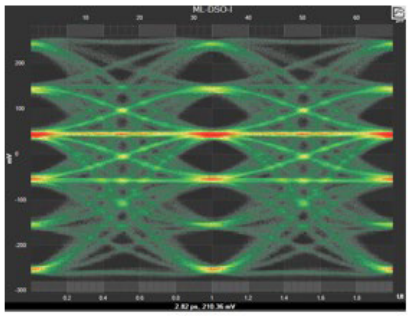
ML9004F



32.5G NRZ Signal



32.5G PAM4 Signal



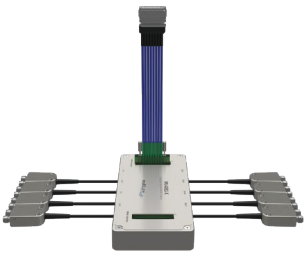
30G PAM6 Signal

	Part Number	Description	Data Format	Details
AWG	**ML9004E**	4-channel Differential Arbitrary Waveform Generator	PAM4/8/6/NRZ	• Sampling rate up to 96GSa/s • Analog bandwidth up to 30GHz • SMPM connectors • PPG Mode: NRZ and PAM4 • AWG Mode pre-programmed waveforms: Square wave, triangular Wave, sinewave, multi-tone, linear chirp, log chirp, sawtooth, exponential rise, exponential decay, Sinc, Lorentz, Surge, Damped Oscillation, Stairs, Serial Data, half-sine, Distorted sinewave and Gaussian
	MW9004E	4-channel Differential Arbitrary Waveform Generator, 2 Dual Channel I/Q	PAM4/8/6/NRZ	
	ML9004F	4-channel Differential Arbitrary Waveform Generator	PAM4/8/6/NRZ	• Sampling rate up to 150GSa/s • Analog bandwidth over 65GHz • SMPM connectors • PPG Mode: NRZ and PAM4 • AWG Mode pre-programmed waveforms: Square wave, triangular Wave, sinewave, multi-tone, linear chirp, log chirp, sawtooth, exponential rise, exponential decay, Sinc, Lorentz, Surge, Damped Oscillation, Stairs, Serial Data, half-sine, Distorted sinewave and Gaussian
	MW9004F	4-channel Differential Arbitrary Waveform Generator, 2 Dual Channel I/Q	PAM4/8/6/NRZ	

AWGN Injection

A dedicated AWGN injector and Pick-off Tee board, respectively, the ML4081 and ML4081-X are designed to highlight the effects of noise on both a signal's BER and eye diagram. Used in a setup with a BERT, a clean signal is passed through the ML4081-X, where the ML4081 injects random noise. The resulting lossy signal is then routed to an awaiting DSO for the eye diagram, and looped back into the BERT to check the effect on the BER. The ML4081/ML4081-X are ideal for use in BIST applications for ATE, margin testing services, or PCIe BIST test applications.

ML4081



ML4081-X

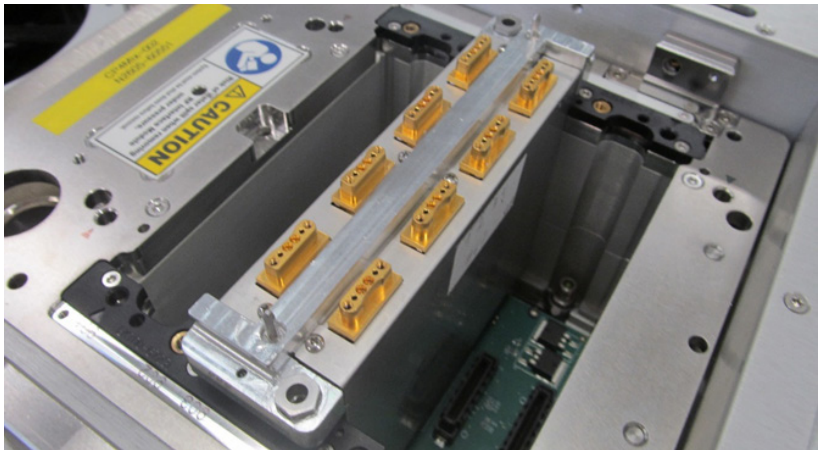
	Part Number	Description	Details
AWGN	**ML4081E**	AWGN Generator	• Crest Factor >5 • 4 differential or 8 single ended channels • Programmable Bandwidth 1-30 GHz • Amplitude -30 dBm to -2 dBm • Programmable Spectral Shaping • Calibrated Amplitude accuracy 2 % • Amplitude noise resolution 0.3 Db • 2.4 dB Noise flatness to 30 GHz
	ML4081-X	Pick-off tee board Routing clean and noise Add crosstalk	• 8 or 16 differential Lanes • Routing for both clean and Noisy Signals • Creates a defined stress source for receivers under test

ATE Instruments

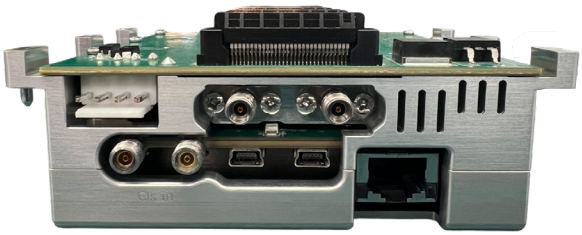
Advantest and MultiLane offer an integrated platform combining MultiLane's high-speed BERT, DSO scope, and AWG instruments with Advantest's V93000 ATE tester. This solution enhances semiconductor IC testing, supporting up to 32 differential lanes at 224 Gbps (PAM4) and 70 GHz bandwidth. The V93000 Smartest software and docking solutions are widely deployed and proven in production environments.

Key Features

- Up to 224 Gbps at -speed device testing
- Up to 96 Channels
- Cabling solution minimizes insertion losses
- Water cooling features
- SMPX connectors covering a frequency range up to 110 GHz per lane
- Hard docking to wafer probes

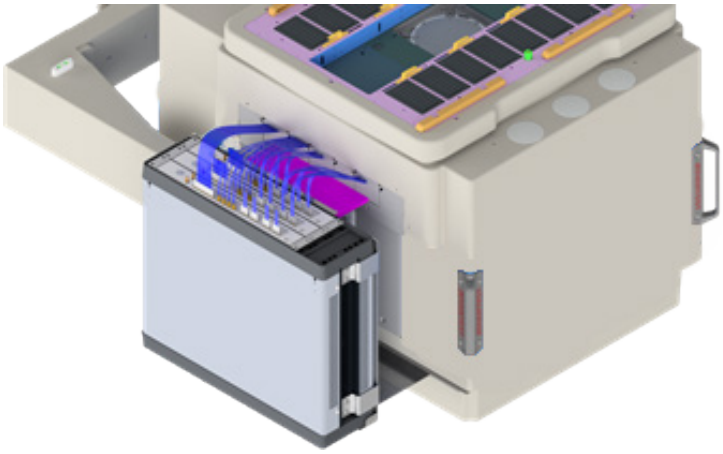


OT4025F DSO mounted is a system for wafer sort testing



OT6000 Backplane

	Part Number	Description
ATE Instruments	**OT6000**	6 Slots Backplane | 12V, 15A power supply | clock cabling, UART and firmware upgrade interfaces | Ethernet connectivity | water cooling intake.
	OT4025F	4 channel 70GHz Digital Sampling Oscilloscope
	OT4039F	4 channel 224 Gbps (112 GBaud) BERT



OT93000 - MWTP system setup

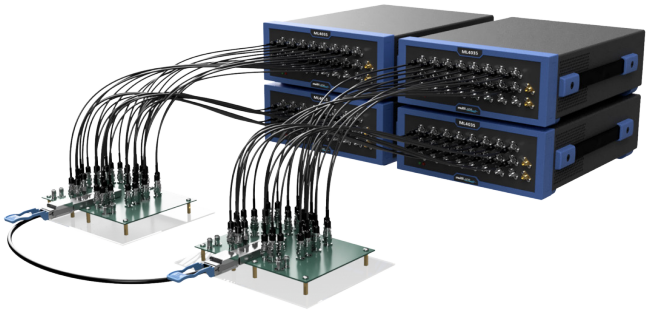
The MWTP is a new module designed to integrate with the OT93000 system, enhancing its testing capabilities with advanced features for better performance and flexibility. It houses BERTs, DSOs, and AWGs in the Twinning Frame under the load board, minimizing the signal path to improve signal integrity and test accuracy. The module offers a compact design, cost-effectiveness, versatile setup, reduced test time, and supports a wide range of ATE systems and instruments, all while being modular and adaptable for various configurations.
has context menu

MultiLane Legacy Cable Testing So lutions

Multiport Cable Testers

MultiLane passive copper testers are the fastest on the market, capturing S-parameter measurements on 16 differential lanes in seconds while providing the industry's simplest calibration procedure.

Optimized for high-volume manufacturing, incoming inspection, RMA, and high-density backplane cables, our multiport cable testing solutions are scalable to over 64 ports.
Making full use of our 3 in 1 BERT, TDR, and DSO, the ML4035, the user-friendly setup can be fully automated to generate a pass/fail report based on time and frequency domain measurements including insertion loss, return loss, crosstalk, and TDR.

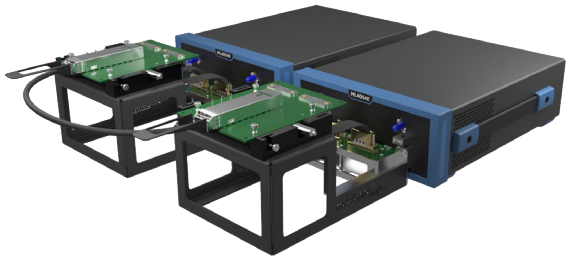


ML1105 Passive Copper Tester

Active Copper Testers

MultiLane covers the full range of active copper testing, with redriver and retimer solutions for Active Copper Cables (ACC) and Active Electrical Cables (AEC) respectively. Our AEC testing is fully HiWire compliant, using our ML4054E 800G BERTs for real hardware pre- and post-FEC measurements and CMIS validation.

Our ACC solution – which uses our ML4035 3 in 1 BERT, TDR, and DSO – is the fastest on the market, capturing S-parameter measurements on 16 differential lanes in seconds, while providing the industry's simplest calibration procedure. All our active cable solutions include fully automated pass/fail report generation, BER, eye diagram, and S-parameter/crosstalk testing, making them ideal for R&D, manufacturing, and RMA.



Active Cable Tester

The ML4079ELN's high equalization capabilities makes it the go-to solution for testing both active and passive interconnects. Users can validate BER, FEC, and push DUT limitations to their full extent, with built in noise injection.

Long Reach Interconnect Testing

Legacy Products

MultiLane continues to offer legacy products due to popular demand, while supplies lasts. Please inquire with your local sales representative about availability.

multiLane

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